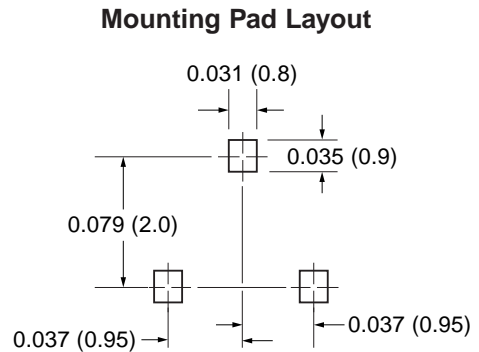
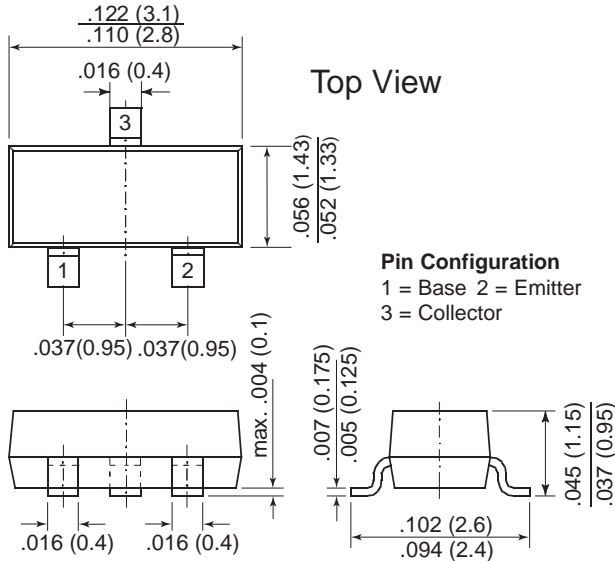




### Small Signal Transistor (NPN)



TO-236AB (SOT-23)



### Features

- NPN Silicon Epitaxial Planar Transistor for switching and amplifier applications.
- As complementary type, the PNP transistor MMBT3906 is recommended.
- This transistor is also available in the TO-92 case with the type designation 2N3904.

### Mechanical Data

- Case:** SOT-23 Plastic Package
- Weight:** approx. 0.008g
- Marking Code:** 1AM
- Packaging Codes/Options:**  
E8/10K per 13" reel (8mm tape), 30K/box  
E9/3K per 7" reel (8mm tape), 30K/box

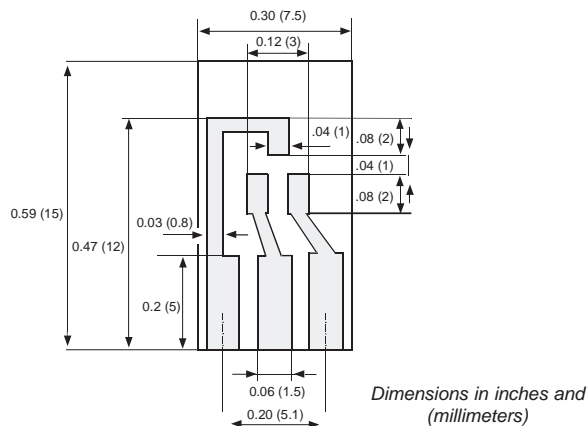
### Maximum Ratings & Thermal Characteristics Ratings at 25°C ambient temperature unless otherwise specified.

Parameter	Symbol	Value	Unit
Collector-Base Voltage	V <sub>CBO</sub>	60	V
Collector-Emitter Voltage	V <sub>CEO</sub>	40	V
Emitter-Base Voltage	V <sub>EBO</sub>	6.0	V
Collector Current	I <sub>C</sub>	200	mA
Power Dissipation at T <sub>A</sub> = 25°C	P <sub>tot</sub>	225 <sup>(1)</sup> 300 <sup>(2)</sup>	mW
Thermal Resistance Junction to Substrate Backside	R <sub>θSB</sub>	320 <sup>(1)</sup>	°C/W
Thermal Resistance Junction to Ambient Air	R <sub>θJA</sub>	450 <sup>(1)</sup>	°C/W
Junction Temperature	T <sub>j</sub>	150	°C
Storage Temperature Range	T <sub>s</sub>	-65 to +150	°C

**Note:** (1) Device on fiberglass substrate, see layout.  
(2) Device on alumina substrate.

## Electrical Characteristics (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
DC Current Gain	h <sub>FE</sub>	V <sub>CE</sub> = 1 V, I <sub>C</sub> = 0.1 mA	40	—	—	—
		V <sub>CE</sub> = 1 V, I <sub>C</sub> = 1 mA	70	—	—	
		V <sub>CE</sub> = 1 V, I <sub>C</sub> = 10 mA	100	—	300	
		V <sub>CE</sub> = 1 V, I <sub>C</sub> = 50 mA	60	—	—	
		V <sub>CE</sub> = 1 V, I <sub>C</sub> = 100 mA	30	—	—	
Collector-Base Breakdown Voltage	V <sub>(BR)CBO</sub>	I <sub>C</sub> = 10 μA, I <sub>E</sub> = 0	60	—	—	V
Collector-Emitter Breakdown Voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> = 1 mA, I <sub>B</sub> = 0	40	—	—	V
Emitter-Base Breakdown Voltage	V <sub>(BR)EBO</sub>	I <sub>E</sub> = 10 μA, I <sub>C</sub> = 0	6.0	—	—	V
Collector Saturation Voltage	V <sub>CEsat</sub>	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 1 mA	—	—	0.2	V
		I <sub>C</sub> = 50 mA, I <sub>B</sub> = 5 mA	—	—	0.3	
Base Saturation Voltage	V <sub>BEsat</sub>	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 1 mA	—	—	0.85	V
		I <sub>C</sub> = 50 mA, I <sub>B</sub> = 5 mA	—	—	0.95	
Collector-Emitter Cut-off Current	I <sub>CEV</sub>	V <sub>EB</sub> = 3 V, V <sub>CE</sub> = 30 V	—	—	50	nA
Emitter-Base Cut-off Current	I <sub>EBV</sub>	V <sub>EB</sub> = 3 V, V <sub>CE</sub> = 30 V	—	—	50	nA
Gain-Bandwidth Product	f <sub>T</sub>	V <sub>CE</sub> = 20 V, I <sub>C</sub> = 10 mA f = 100 MHz	300	—	—	MHz
Collector-Base Capacitance	C <sub>CBO</sub>	V <sub>CB</sub> = 5 V, f = 100 kHz	—	—	4	pF
Emitter-Base Capacitance	C <sub>EBO</sub>	V <sub>EB</sub> = 0.5 V, f = 100 kHz	—	—	8	pF



### Layout for R<sub>thJA</sub> test

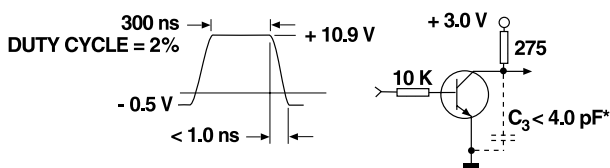
Thickness: Fiberglass 0.059 in (1.5 mm)

Copper leads 0.012 in (0.3 mm)

**Electrical Characteristics** ( $T_J = 25^\circ\text{C}$  unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Noise Figure	NF	$V_{CE} = 5\text{ V}, I_C = 100\ \mu\text{A}, R_G = 1\ \text{k}\Omega, f = 10\dots 15000\ \text{Hz}$	—	—	5	dB
Input Impedance	$h_{ie}$	$V_{CE} = 10\ \text{V}, I_C = 1\ \text{mA}, f = 1\ \text{kHz}$	1	—	10	$\text{k}\Omega$
Small Signal Current Gain	$h_{fe}$	$V_{CE} = 10\ \text{V}, I_C = 1\ \text{mA}, f = 1\ \text{kHz}$	100	—	400	—
Voltage Feedback Ratio	$h_{re}$	$V_{CE} = 10\ \text{V}, I_C = 1\ \text{mA}, f = 1\ \text{kHz}$	$0.5 \cdot 10^{-4}$	—	$8 \cdot 10^{-4}$	—
Output Admittance	$h_{oe}$	$V_{CE} = 1\ \text{V}, I_C = 1\ \text{mA}, f = 1\ \text{kHz}$	1	—	40	$\mu\text{S}$
Delay Time (see Fig. 1)	$t_d$	$I_{B1} = 1\ \text{mA}, I_C = 10\ \text{mA}$	—	—	35	ns
Rise Time (see Fig. 1)	$t_r$	$I_{B1} = 1\ \text{mA}, I_C = 10\ \text{mA}$	—	—	35	ns
Storage Time (see Fig. 2)	$t_s$	$-I_{B1} = I_{B2} = 1\ \text{mA}, I_C = 10\ \text{mA}$	—	—	200	ns
Fall Time (see Fig. 2)	$t_f$	$-I_{B1} = I_{B2} = 1\ \text{mA}, I_C = 10\ \text{mA}$	—	—	50	ns

**Fig. 1:** Test circuit for delay and rise time  
 \* total shunt capacitance of test jig and connectors



**Fig. 2:** Test circuit for storage and fall time  
 \* total shunt capacitance of test jig and connectors

